Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/695,791	TANAKA ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

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SEARCHED				
Class	Subclass	Date	Examiner	
250	214R, 231.13, 231.14, 231.18	9/15/2005	PL	
356	614, 616	9/15/2005	PL	
341	13	9/15/2005	PL	
33	1PT	9/15/2005	PL	
250	208.1	9/15/2005	PL	
250	208.2	9/15/2005	PL	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
<u> </u>					

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
East (see attached)	3/23/2005	PL
Consulted w/ S. Allen	4/5/2005	PL
East (see attached)	4/6/2005	PL
East (see attached)	4/11/2005	PL
East (see attached)	4/12/2005	PL
East (see attached)	9/15/2005	PL